

Notice of References Cited	Application/Control No. 10/646,918		Applicant(s)/Patent Under Reexamination KIM, YOUNG-SE	
	Examiner Huy D. Nguyen		Art Unit 2617	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,748,249	06-2004	Eromaki et al.	455/575.4
*	B	US-2003/0143961	07-2003	Humphreys et al.	455/90
*	C	US-2002/0065102	05-2002	Miyake et al.	455/556
*	D	US-2001/0027121	10-2001	Boesen, Peter V.	455/556
*	E	US-6,850,226	02-2005	Finke-Anlauff, Andrea	345/169
*	F	US-6,397,078	05-2002	Kim, Young S.	455/556.2
*	G	US-2003/0003878	01-2003	Bestle, Nikolaj Heiberg	455/90
*	H	US-2002/0137476	09-2002	Shin, Ji Seop	455/90
*	I	US-2003/0103041	06-2003	Nguyen et al.	345/168
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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